Adam’s background in Electrical Engineering manifested with his undergraduate degree from University of Illinois at Urbana Champaign and his graduate degree from Georgia Tech before joining IBM in 2016. Adam started his work in IBM as part of the characterization team and was involved with the entire process of bringing up 14HP Technology. His responsibilities mainly revolved around 14HP in-line SRAM yield health which is a major indicator of WFT health as well as an ideal place to pick up and track defect patterns. Because of this, Adam specialized in identifying and diagnosing defect signatures that impaired our product yields such as Fin Residue and OS Swath Defects.

Early on in his career at IBM, Adam realized the role that data plays in all aspects of technology design. This prompted him to pursue a second master’s degree from UC Berkeley’s Master of Information and Data Science program from which he graduated from in December 2019. He picked up new skills which enabled him to develop the Fin Res Metric that accurately labels all wafers with the Fin Residual defect as well as assigning a level of severity to the wafer. This came to be very useful in the process of eliminating Fin Residuals and improving the in-line SRAM yield. From this project, he discovered a profound interest in model building and abstracting information from obscure data and he aims to continue driving technology forward using data science and machine learning tools.